



01-21-05

IFW

Filed Via Express Mail pursuant to 37 C.F.R. 1.10

Rec. No.: EV 479 701 547 US

On: JANUARY 20, 2005

By:

LINDA E. HASTINGS

Any fee due as a result of this paper, not covered by an enclosed check, may be charged on Deposit Acct. No. 50-1290.

Attorney Docket No.: 100806-00244 (NEC 15.938A)

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Inventor: Hisashi YAMAUCHI
Serial No.: 10/736,934
Filed: December 16, 2003
Title: **METHOD OF GENERATING TEST PATTERN
FOR INTEGRATED CIRCUIT**
Examiner: Guy J. Lamarre
Group Art Unit: 2133

Commissioner for Patents
P. O. Box 1450
Alexandria, VA 22313-1450

AMENDMENT

SIR:

In response to the Office Action mailed on October 20, 2004, the period for responding thereto having been set to expire after January 20, 2005, please amend the subject application as follows: